

No.1333C

NPN Planar Silicon Darlington Transistor

Driver Applications

Applications

· Suitable for use in switching of L load (motor drivers, printer hammer drivers, relay drivers).

Features

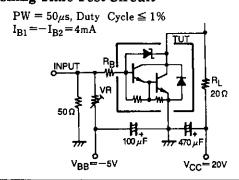
- · High DC current gain.
- · Large current capacity and wide ASO.
- \cdot On-chip Zener diode of $60\pm10 \text{V}$ between collector and base.
- · Uniformity in collector-to-base breakdown voltage due to the adoption of an accurate impurity diffusion process.
- · High inductive load handling capability.

Absolute Maximum Ratings at	t Ta = 25°C			unit
Collector-to-Base Voltage	V_{CBO}		50 ※	V
Collector-to-Emitter Voltage	V_{CEO}		50 <u>%</u>	v
Emitter-to-Base Voltage	V_{EBO}		6	v
Collector Current	Ic		2	Å
Collector Current (Pulse)	I_{CP}		4	A
Base Current	IB		0.4	A
Collector Dissipation	$\tilde{P_C}$	$Tc = 25^{\circ}C$	20	w
Junction Temperature	Τj̈́		150	°C
Storage Temperature	Tstg		-55 to +150	°C

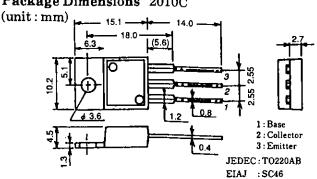
	_	-			
> /	. 337:41	7	2:-2-1	$(CO \pm 1.037)$	
X .	; ** 161	Lener	aroae ($(60\pm10V)$	

Electrical Characteristics at Ta = 25°C				typ	max	unit
Collector Cutoff Current	I_{CBO}	$V_{CB} = 40V, I_E = 0$, -	• 5 P	10	μA
Emitter Cutoff Current	I_{EBO}	$V_{EB} = 5V_{IC} = 0$			2	mΑ
DC Current Gain	$\mathbf{h_{FE}}$	$V_{CE} = 5V_{IC} = 1A$	1000	4000	_	
Gain-Bandwidth Product	$\mathbf{f_T}$	$V_{CE} = 5V, I_C = 1A$		180		MHz
C-E Saturation Voltage	$\mathbf{v}_{\mathbf{CE}(\mathbf{sat})}$	$I_C=1A,I_B=4mA$		1.0	1.5	V
B-E Saturation Voltage	$V_{\mathrm{BE}(\mathrm{sat})}$	$I_C = 1A, I_B = 4mA$			2.0	v
C-B Breakdown Voltage	$V_{(BR)CBO}$	$I_C = 0.1 \text{mA}, I_E = 0$	50	60	70	Ÿ
C-E Breakdown Voltage	$V_{(BR)CEO}$	$I_C = 1 \text{ mA}, R_{BE} = \infty$	50	60	70	v
Inductive Load Handling	Es/b	$L=100mH, R_{BE}=100\Omega$	25			mJ
Capability						
Turn-ON Time	$\mathbf{t_{on}}$	$V_{CC} = 20V, I_C = 1A,$		0.2		μs
Storage Time	t_{stg}	$I_{B1} = -I_{B2} = 4mA$		3.5		นธ
Fall Time	t_f			0.5		IIS

Switching Time Test Circuit



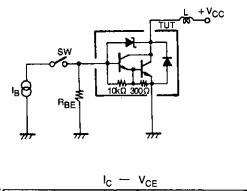
Package Dimensions 2010C

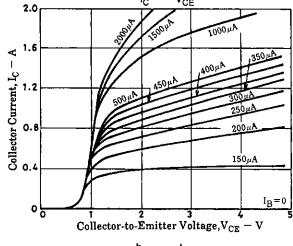


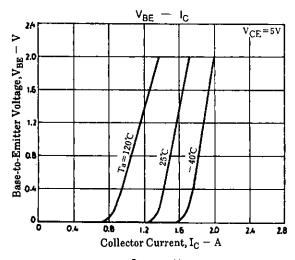
SANYO Electric Co., Ltd. Semiconductor Business Headquarters TOKYO OFFICE Tokyo Bldg., 1-10, 1 Chome, Ueno, Taito-ku, TOKYO, 110 JAPAN

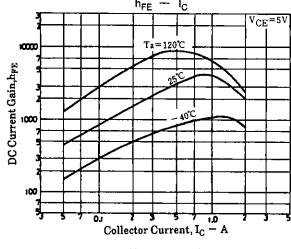
Es/b Test Circuit

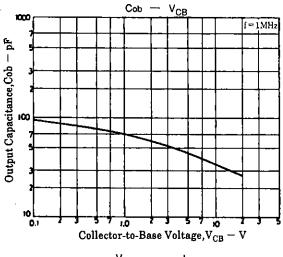
 V_{CC} =20V, R_{BE} =100 Ω

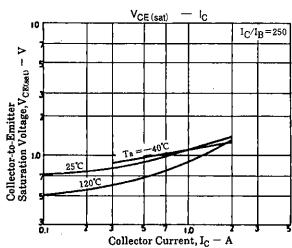


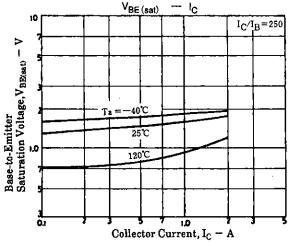


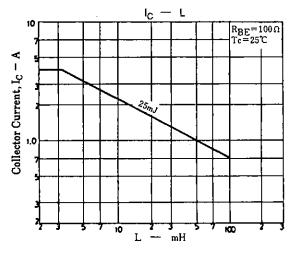


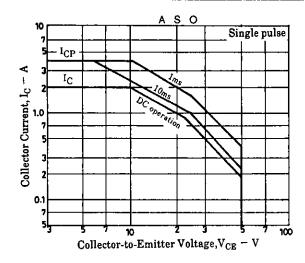


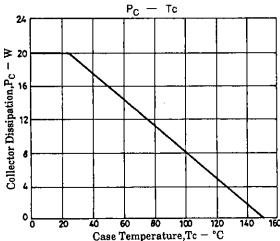












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